

Notice of References Cited	Application/Control No. 10/729,609	Applicant(s)/Patent Under Reexamination MCWAID ET AL.	
	Examiner Daniel S. Larkin	Art Unit 2856	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,497,656	03-1996	Kado et al.	73/105
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Griffith, J.E. et al., "Dimensional Metrology with Scanning Probe Microscopes" J. Appl. Phys. Vol. 74, No. 9, 1 November 1993, pp. R83-R109.
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.